Notice of References Cited	Application/Control No. 18/822,013	Applicant(s)/Patent Under Reexamination MUTHU et al.	
	Examiner PAN CHOY	Art Unit 3624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date YYYY-MM-DD	Name	CPC Classification	US Classification
*	A	US-20220253871-A1	2022-08-11	Miller; Travis J.	G06F16/36	1/1
*	B	US-20180096365-A1	2018-04-05	Noyes; Thomas	G06Q40/04	1/1
*	C	US-20240061833-A1	2024-02-22	Tangari; Gioacchino	G06F16/243	1/1
*	D	US-20220382785-A1	2022-12-01	Patel; Pritesh	G06F16/24575	1/1
*	E	US-20220192562-A1	2022-06-23	HAYES; James S.	G06N3/0442	1/1
*	F	US-20190034796-A1	2019-01-31	LI; Xin	G06N3/044	1/1
*	G	US-20220012535-A1	2022-01-13	Ben-Itzhak; Yaniv	G06F18/2148	1/1
	H					
	I					
	J					
	K					
	L					
	M					

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date YYYY-MM-DD	Country	Name	CPC Classification
*	N	CN-118013846-A	2024-05-10	CN	YOU, Yan-cheng	G06F18/243
*	O	CN-109002752-A	2018-12-14	CN	ZHANG, FENG	G06F18/24
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
	U	Soori et al., "Artificial Neural Networks in Supply Chain Management, A Review", HAL Open Science, Journal of Economy and Technology. 12 December 2023. (Year: 2023)
	V	Wichmann et al., "Extracting Supply Chain maps from news articles using deep neural networks", Institute for Manufacturing, University of Cambridge, United Kingdom. September 7, 2019. (Year: 2019)
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in YYYY-MM-DD format are publication dates. Classifications may be US or foreign.